

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEOUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

CUSTOMER DEVICE UNDER THE TEST SUPPORT INFORMATION

EMC LABORATORY TEL: 647-435-0140

DUT NAME	<input type="text"/>	ABBREVIATION	<input type="text"/>
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DUT MODEL	<input type="text"/>
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HW REVISION	<input type="text"/>	SW REVISION	<input type="text"/>	COMMUNICATION BUS	<input type="text"/>
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OEM	<input type="text"/>	SEVERITY LEVEL	<input type="text"/>
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DUT TYPE (1)	<input type="text"/>
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DUT TYPE (2)	<input type="text"/>
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DUT TYPE (3)	<input type="text"/>
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FUNCT GROUP	<input type="text"/>
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TEST PLAN REF	<input type="text"/>	PROJECT REF	<input type="text"/>	TARGET DATE	<input type="text"/>
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<input type="text"/>

<input type="text"/>

System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
 Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
 Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
 DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
 Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
 Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
 Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
 Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
 Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
 DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
 Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
 Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
 Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
 Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
 Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
 Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
 Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
 Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to the usual supply voltages EQ/TE 01		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTRICAL PERFORMANCE COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



Provide DUT activation specific information here ...

SAMPLES	3	PINS	10	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$1,198.52
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
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QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD Resistance to the slow fall and slow rise of the supply voltage EQ/TE 02

TEST PURPOSE DESIGN VALIDATION

TEST TYPE ELECTRICAL PERFORMANCE COMPONENT LEVEL

SPEC TITLE Environment specifications of electric and electronic equipment electrical characteristics

SPEC INDEX B21 7110

SPEC REVISION ind C

SPEC REL DATE

REFERENCE (1) 20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com

REFERENCE (2) B35 0010 ind OR - EMC & Electrical Test Plan



SAMPLES 3

PINS 10

MODES 1

CYCLE 2

LAB BUILT HARNESSES

QUOTE THIS TEST METHOD

Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE

\$676.55

EDIT

+

^

v

x

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QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Test of resetting EQ/TE 03		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTRICAL PERFORMANCE COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	3	PINS	10	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$650.30**

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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
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EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to unusual voltages EQ/TE 04		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTRICAL PERFORMANCE COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	3	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$302.51**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
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EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD Resistance to ground and to positive on the positive terminal connections EQ/TE 05

TEST PURPOSE DESIGN VALIDATION

TEST TYPE ELECTRICAL PERFORMANCE COMPONENT LEVEL

SPEC TITLE Environment specifications of electric and electronic equipment electrical characteristics

SPEC INDEX B21 7110

SPEC REVISION ind C

SPEC REL DATE

REFERENCE (1) 20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com

REFERENCE (2) B35 0010 ind OR - EMC & Electrical Test Plan



SAMPLES 3

PINS 2

MODES 1

CYCLE 2

LAB BUILT HARNESSES

QUOTE THIS TEST METHOD

Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE

\$880.57

EDIT

+

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v

x

System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
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EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to exceptional supply voltage (18V) EQ/TE 07		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTRICAL PERFORMANCE COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	3	PINS	1	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
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Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$1,113.79**

	EDIT	+	^	v	x
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EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Pulse 1 and 2a EQ/IC 01	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
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SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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TEST METHOD COST ESTIMATE **\$734.79**

	EDIT	+	^	v	x
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Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
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Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD Pulse 3a and 3b EQ/IC 02

TEST PURPOSE DESIGN VALIDATION

TEST TYPE ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL

SPEC TITLE Environment specifications of electric and electronic equipment electrical characteristics

SPEC INDEX B21 7110

SPEC REVISION ind C

SPEC REL DATE

REFERENCE (1) 20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com

REFERENCE (2) B35 0010 ind OR - EMC & Electrical Test Plan



SAMPLES 2

PINS 1

MODES 1

CYCLE 2

LAB BUILT HARNESSES

QUOTE THIS TEST METHOD

Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE

\$860.83

EDIT

+

^

v

x

System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Pulse 5b EQ/IC 03		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



Load Dump

SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$432.16**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to the power micro cuts EQ/IC 04		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	2	PINS	10	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$534.01
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to pulses 4 or 4bis EQ/IC 05	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$544.95**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to the internal power system undulations EQ/IC 06		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTRICAL PERFORMANCE COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	3	PINS	1	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$584.61
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV; A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to the transients on the signal lines EQ/IC 07 (Pulse 3a, 3b)		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



Transients on signal lines

SAMPLES	2	PINS	10	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$980.93
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to the current injection (BCI)	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$2,206.23**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Resistance to restart pulse EQ/IC 12	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	10	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$1,014.27**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to radiated field EQ/IR 01	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$3,413.31**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to the low frequency magnetic field EQ/IR 02		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$940.83
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	ESD Handling EQ/IR 03	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	10	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$743.20**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	ESD Powered EQ/IR 04	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$894.16**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to the field radiated in reverberating room EQ/IR 06	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$3,366.64**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Commutation noises measurement test EQ/MC 01		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE	\$511.95
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	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Low frequency leded noises low EQ/MC 02	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	10	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$485.47**

	EDIT	+	^	v	x
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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
Auxiliary mate connectors: provide pinout for all subassemblies in the test setup (motors, solenoids, sensors). Whenever possible use production intent parts.
Auxiliary equipment instructions: assembly & disassembly, operating environment, initialization, correct function evaluation, troubleshooting, special tools.
Communication bus type: consult the our lab for EMC compatible fiber-optic satellite HW/SW availability to develop adequately the test setup communication bus support.
Computers and peripherals: example laptop "A" for CAN bus, laptop "B" for remote buttons activation, laptop "C" for measurements and data acquisition.
DUT functional/parametric verification: develop a fast method to certify and record each sample as good or bad. This method will be used after each immunity test step or method.
Pass/fail criteria grid: define for each pin acceptable V, I, Z tolerances and the expected performance status (e.g. I, II, III, IV) per functional group (e.g. A, B, C, D).
Eliminate false deviations: It is quite rare to have implemented in DUT a perfect diagnostic software at DV stage. Learn and document missing features before each validation.
Critical timing: provide a diagram showing sequentially major functions versus I/O status for a complete DUT activation/monitoring cycle (max dwell time) in each operating mode.
Simulation limitations: a lengthy test can overheat a PWM controlled short duration brush motor load and lower CEV. A stalled motor load may falsely improve CEV.
Data acquisition options: I/O status logged in response to diagnostic messages gives an accurate picture of what MCU is processing based on current SW revision level.
Test samples: label the DUT number, serial, and name on each sample submitted to the EMC lab. Explain differences between multiple test samples numbers/models.
Spare samples: provide a few test samples as backup in case the RF immunity or ESD damages the DUT. Indicate parallel testing options to speedup the validation process.
Technical representative: designate a contact person familiar with the product to be present during the test or remotely assist the EMC lab during the validation testing process.
Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Measure of radio frequency noises transmitted EQ/MC 03		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	2	PINS	2	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$867.80**

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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
Installation instructions: default HW/SW system configuration, verification method, model differences, EMC test method specific options.
DUT operating instructions: SW/HW activation, monitoring method for each operating mode called in the test plan (run, standby, sleep).
Potential source of emissions: list local oscillator, processor clocks, PWM, and periodic interface signals frequencies, relays, magnetic sensors, inductive components.
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Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Magnetic Field Emissions EQ/MR 02		
TEST PURPOSE	DESIGN VALIDATION		
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL		
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics		
SPEC INDEX	B21 7110		
SPEC REVISION	ind C	SPEC REL DATE	
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com		
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan		



SAMPLES	2	PINS	1	MODES	1	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$530.29**

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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
Wiring schematics: DUT's connector pinout diagram, fuses, wires gage, cables routing, exerciser's test points and controls, auxiliary control and simulation equipment.
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Deviation threshold: the initial estimated test time allocated for immunity can dramatically increase when threshold the RF level where a deviation from DUT's expected response occurs. Provide flowchart on how to handle redundant deviations, fails safe mode, and stop test conditions for each function monitored.

EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

WWW.EMCLABINFO.COM

TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD	Immunity to embedded transmitters EQ/IR 05	
TEST PURPOSE	DESIGN VALIDATION	
TEST TYPE	ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL	
SPEC TITLE	Environment specifications of electric and electronic equipment electrical characteristics	
SPEC INDEX	B21 7110	
SPEC REVISION	ind C	SPEC REL DATE
REFERENCE (1)	20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com	
REFERENCE (2)	B35 0010 ind OR - EMC & Electrical Test Plan	



SAMPLES	2	PINS	1	MODES	2	CYCLE	2	<input type="checkbox"/> LAB BUILT HARNESSSES	<input checked="" type="checkbox"/> QUOTE THIS TEST METHOD
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Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE **\$1,176.03**

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System block diagram: DUT I/O, power supplies, grounding, loads, sensors, control signals, communication bus, other electromechanical or electronic subassemblies.
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EMC & ELECTRICAL TEST METHODS QUOTATION FORM



QUOTATION FOR PSA-PEUGEOT-CITROEN TEST METHODS

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TEST METHOD VALIDATION REQUIREMENTS & COST EVALUATION

EMC LABORATORY TEL: 647-435-0140

TEST METHOD Radiated Emissions (0.15 to 2500 MHz) EQ/MR 01

TEST PURPOSE DESIGN VALIDATION

TEST TYPE ELECTROMAGNETIC COMPATIBILITY COMPONENT LEVEL

SPEC TITLE Environment specifications of electric and electronic equipment electrical characteristics

SPEC INDEX B21 7110

SPEC REVISION ind C **SPEC REL DATE**

REFERENCE (1) 20 7010 ind C - Type-approval and conformity of production with regard to electromagnetic com

REFERENCE (2) B35 0010 ind OR - EMC & Electrical Test Plan



Empty text area for additional notes or comments.

SAMPLES 2 **PINS** 1 **MODES** 1 **CYCLE** 2 LAB BUILT HARNESSSES QUOTE THIS TEST METHOD

Edit required information and check "quote this test method" to quote for it.
Click on the drop-down list below for a summary of test method titles under quotation.
Select any item in the list to jump to that test method title page.

TEST METHOD COST ESTIMATE \$1,246.47

Empty text input field with **EDIT** button and navigation icons (+, ^, v, x).

Name **Date**

Company

Address

City **State**

Country Canada **Zip Code**

GRAND TOTAL

\$26,891.16

SUBMIT

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CUSTOMER SIGNATURE :

FLEXAUTOMOTIVE :